

ExB trap emptying design and simulations for the ${}^6\text{He}$ CRES experiment

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${}^6\text{He}$ -CRES



Outline

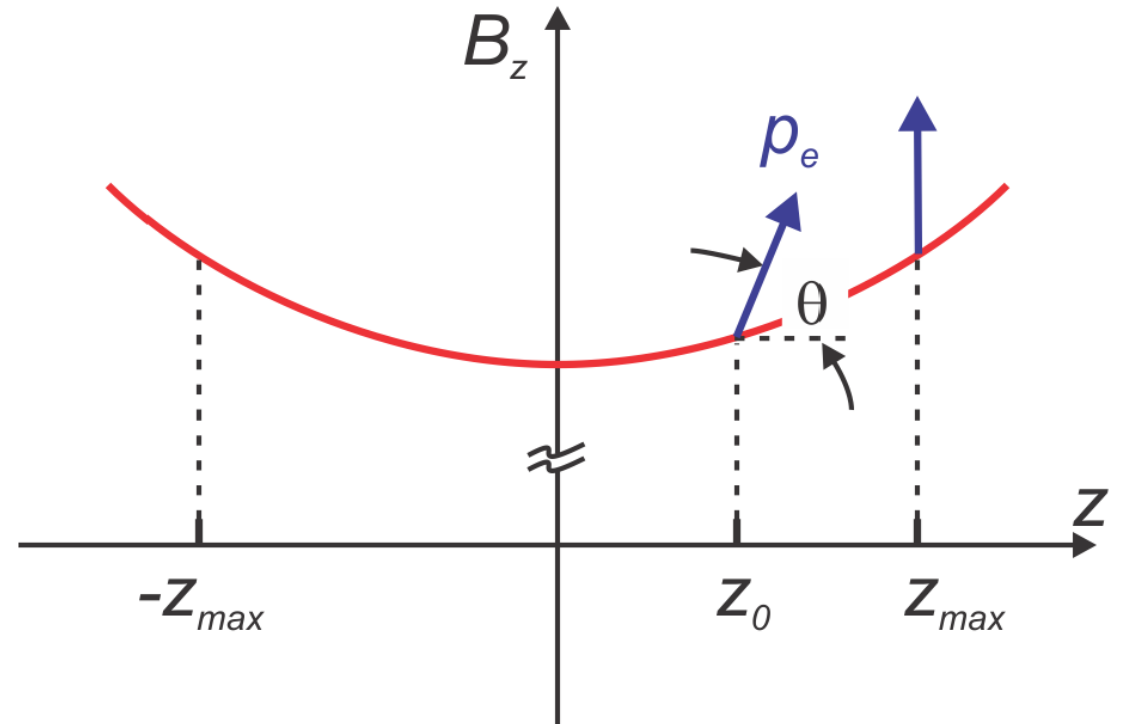
- CRES review
- Trapping field mapping
- ExB trap emptying mechanism
- Constant field proof of concept
- Single electrode tests
- Double electrode tests

Cyclotron Radiation Emission Spectroscopy (CRES)

$$\omega_c = \frac{eB}{m\gamma} = \frac{eB}{m(1 + K/mc^2)}$$

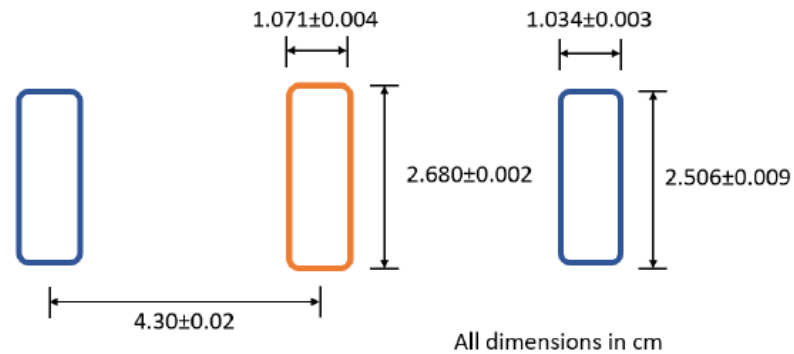
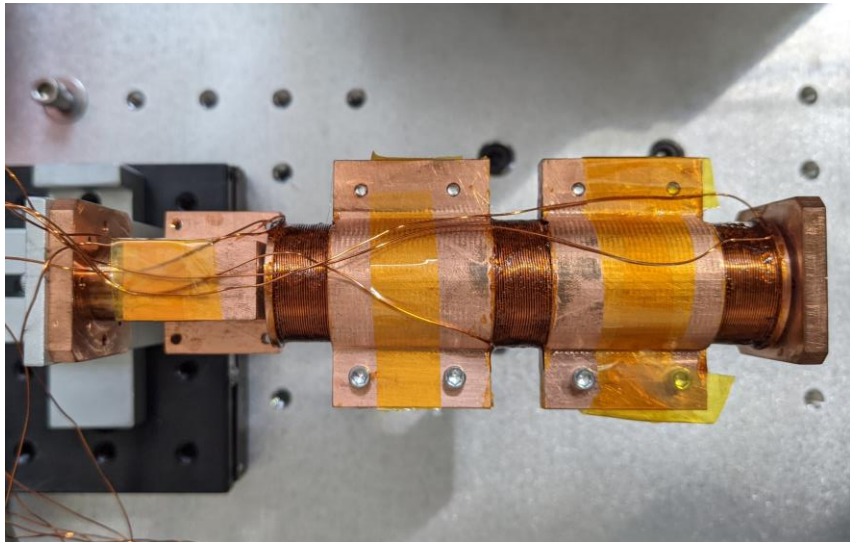
$$r^2 B(z) = \text{constant} = \left(\frac{p \sin \theta(t)}{eB(z)} \right)^2 B(z)$$

$$\frac{\sin^2 \theta(t)}{B(z)} = \text{constant}$$

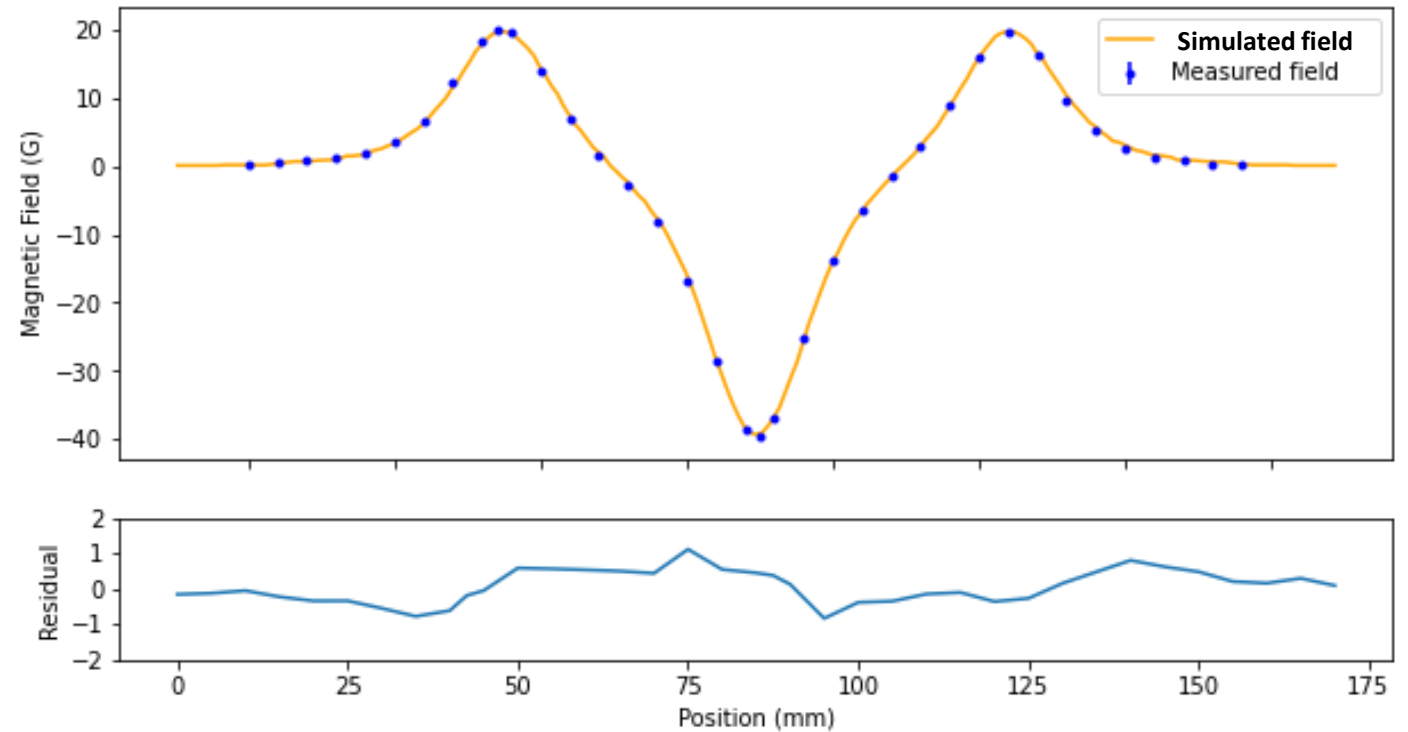
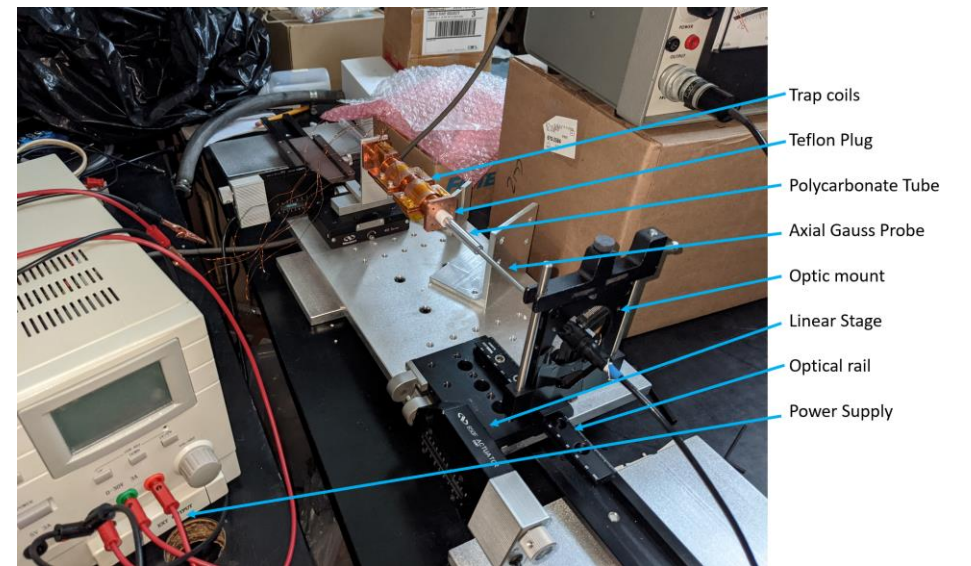


Trapping field mapping

Accurate field shape is needed to simulate trajectories



Trap coil dimensions

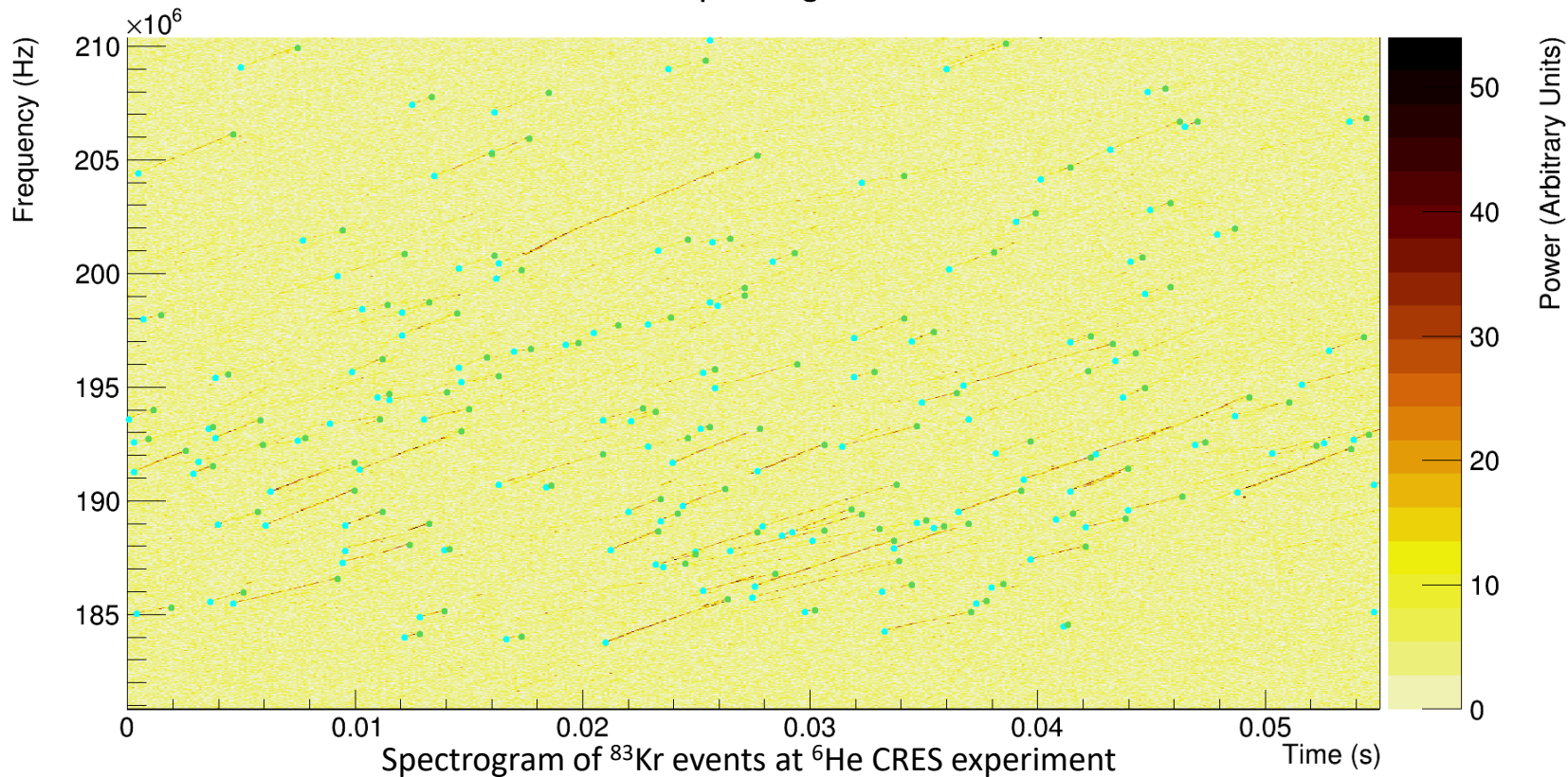


Average rms residual / 20G: 1.95%

ExB trap emptying

Many simultaneous events makes event reconstruction difficult

Spectrogram



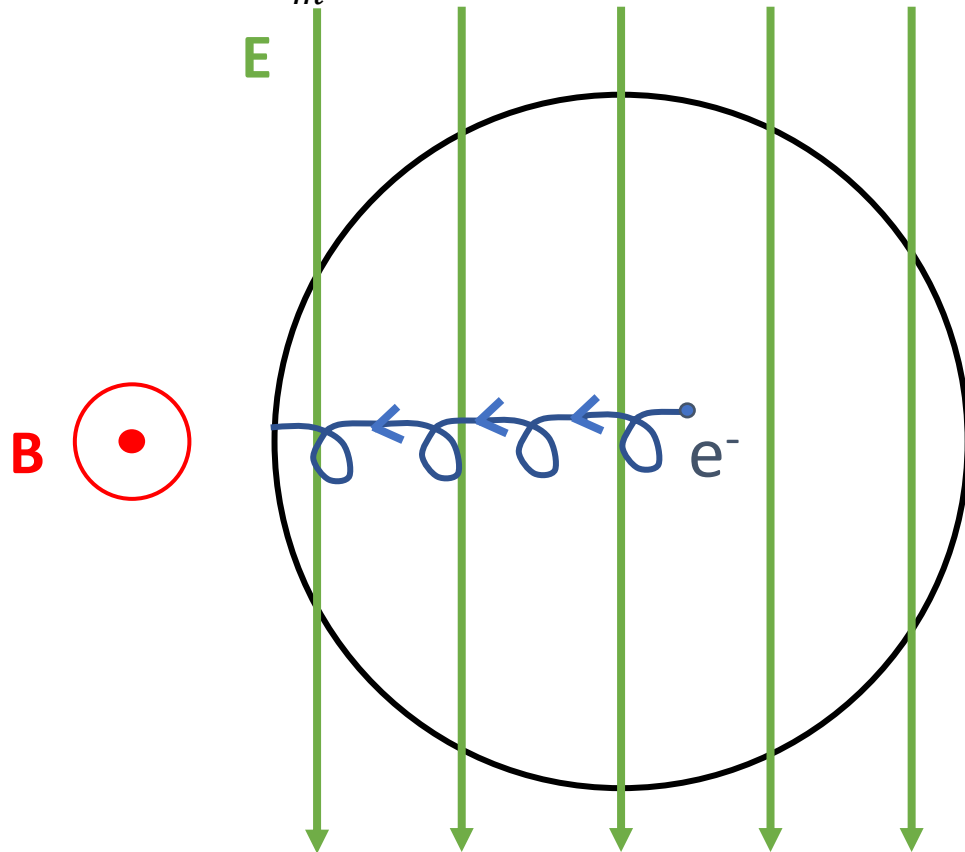
Trap emptying mechanism requirements

- Emptying less than 0.1ms
- Minimal signal loss less than -1dB
 - Signal to Noise ratio decrease from 7->6
- No disturbance of ambient magnetic field
- Compatible with cryogenic and vacuum environment

ExB trap emptying

Uniform fields: $\vec{v}_D = \frac{\vec{E} \times \vec{B}}{B^2}$ (SI units, $B \geq 1$ Tesla)

$$E \approx 2 \times \frac{10^{-2} V}{m} \rightarrow 1 V \text{ to meet } 0.1 \text{ ms}$$



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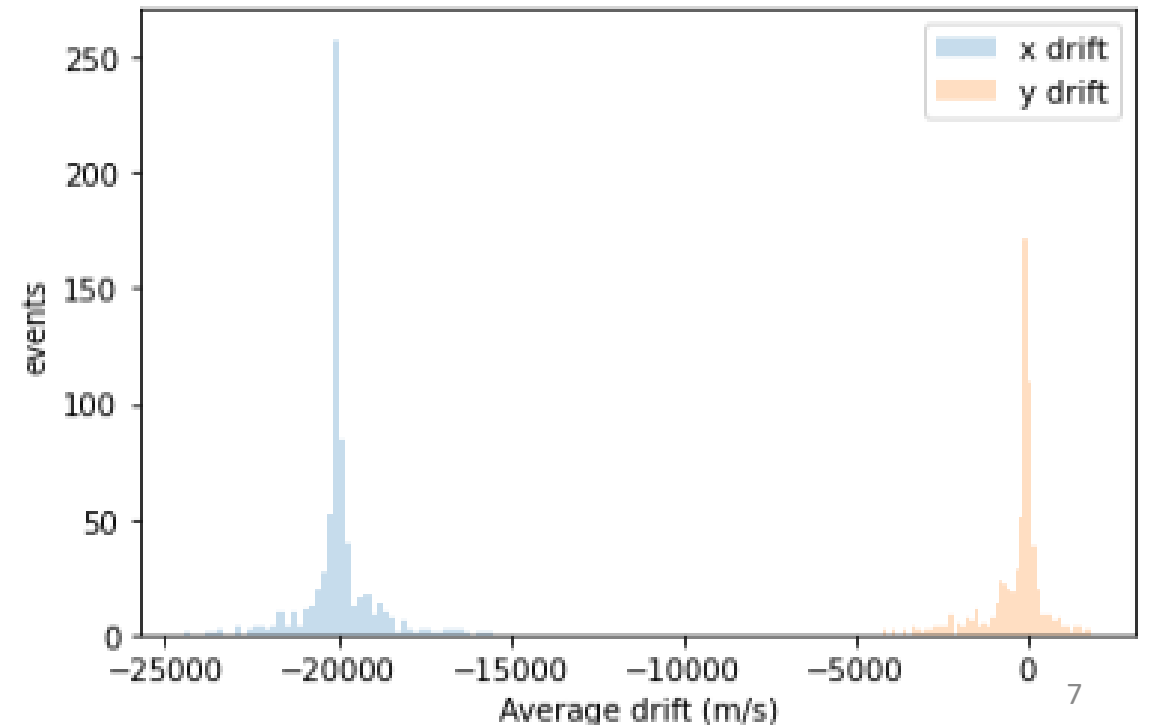
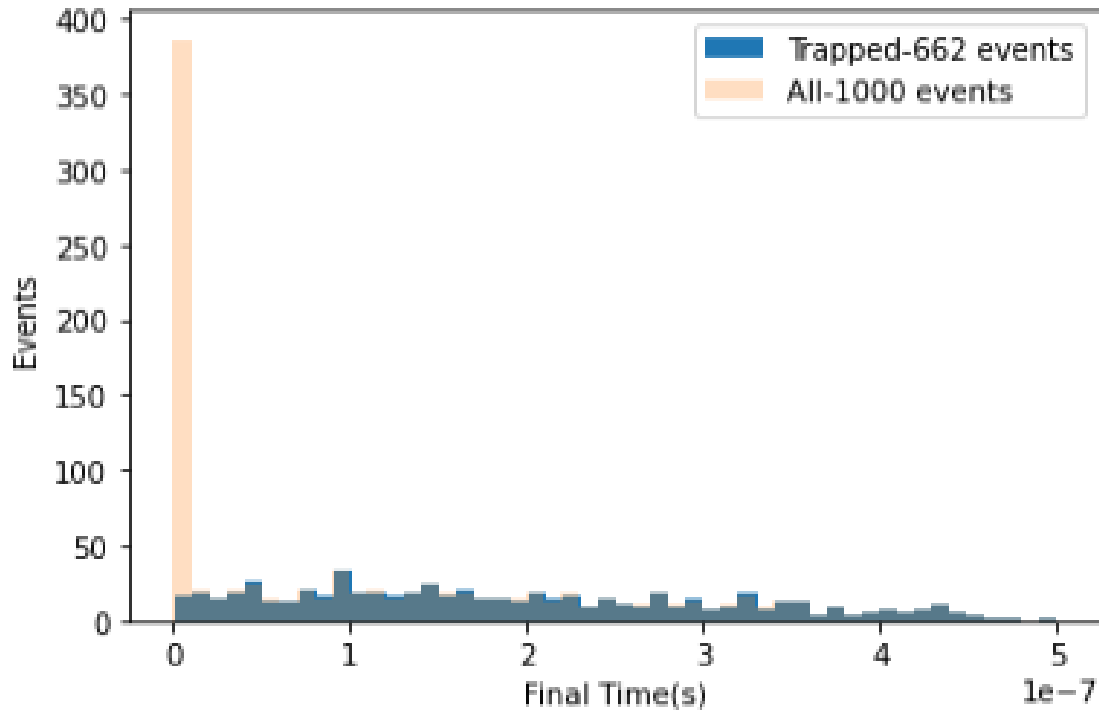
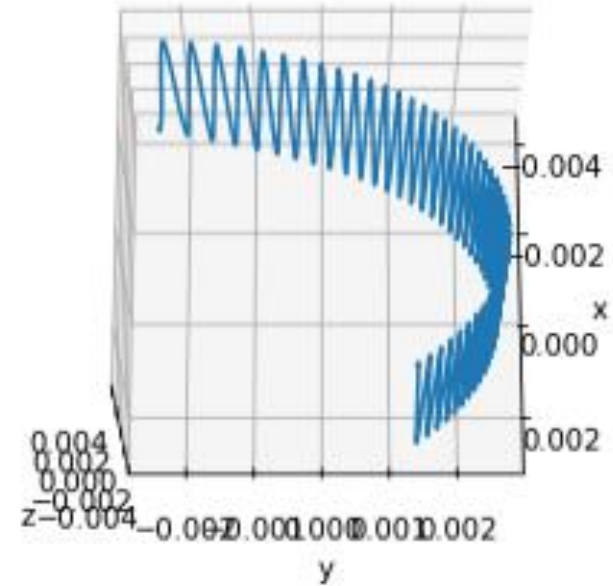
Linear E field simulation

Trap coil field calculation

linear axial B field (1 Tesla)

linear electric field ($-200 \text{ V/cm } \hat{y}$)

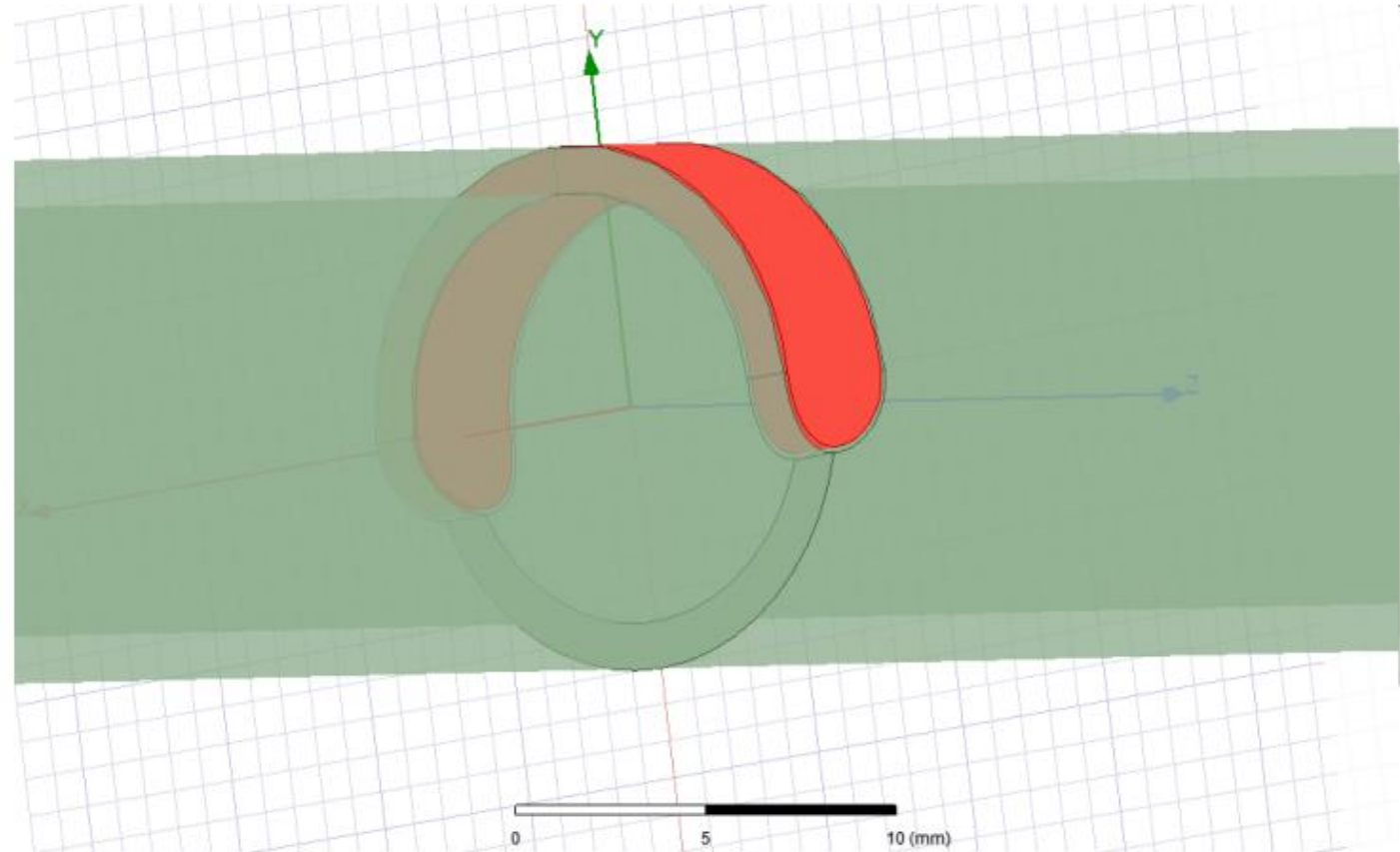
Simulate fields and electron trajectories using Kassiopeia



Single electrode ExB sweeper

Trap emptying mechanism requirements

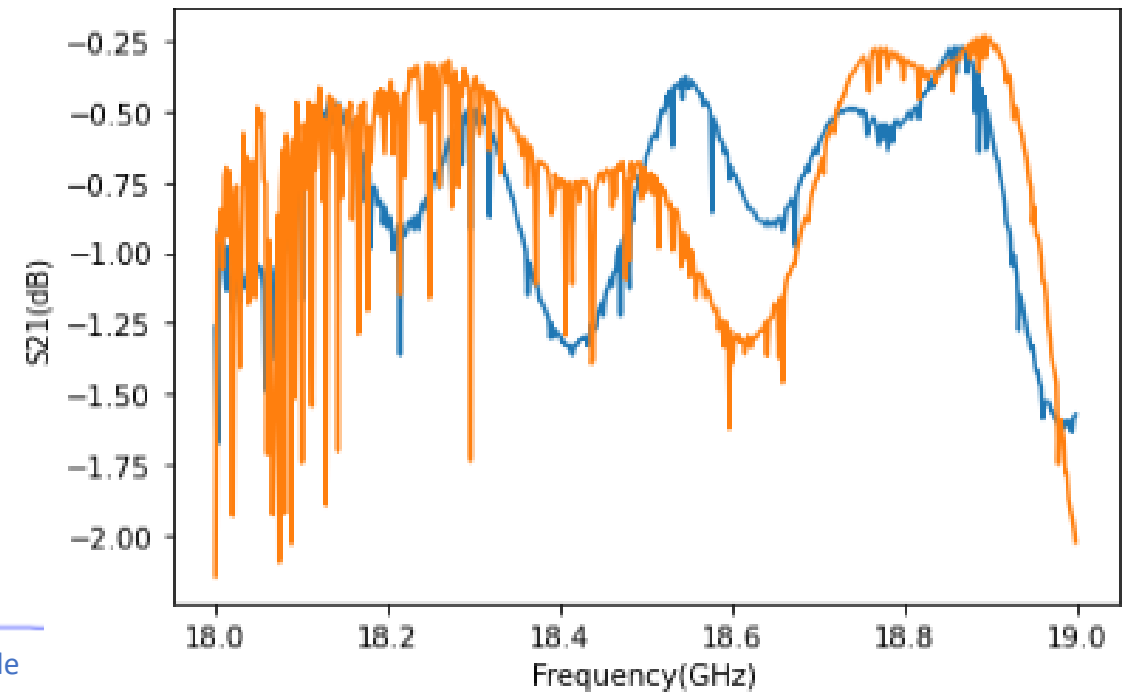
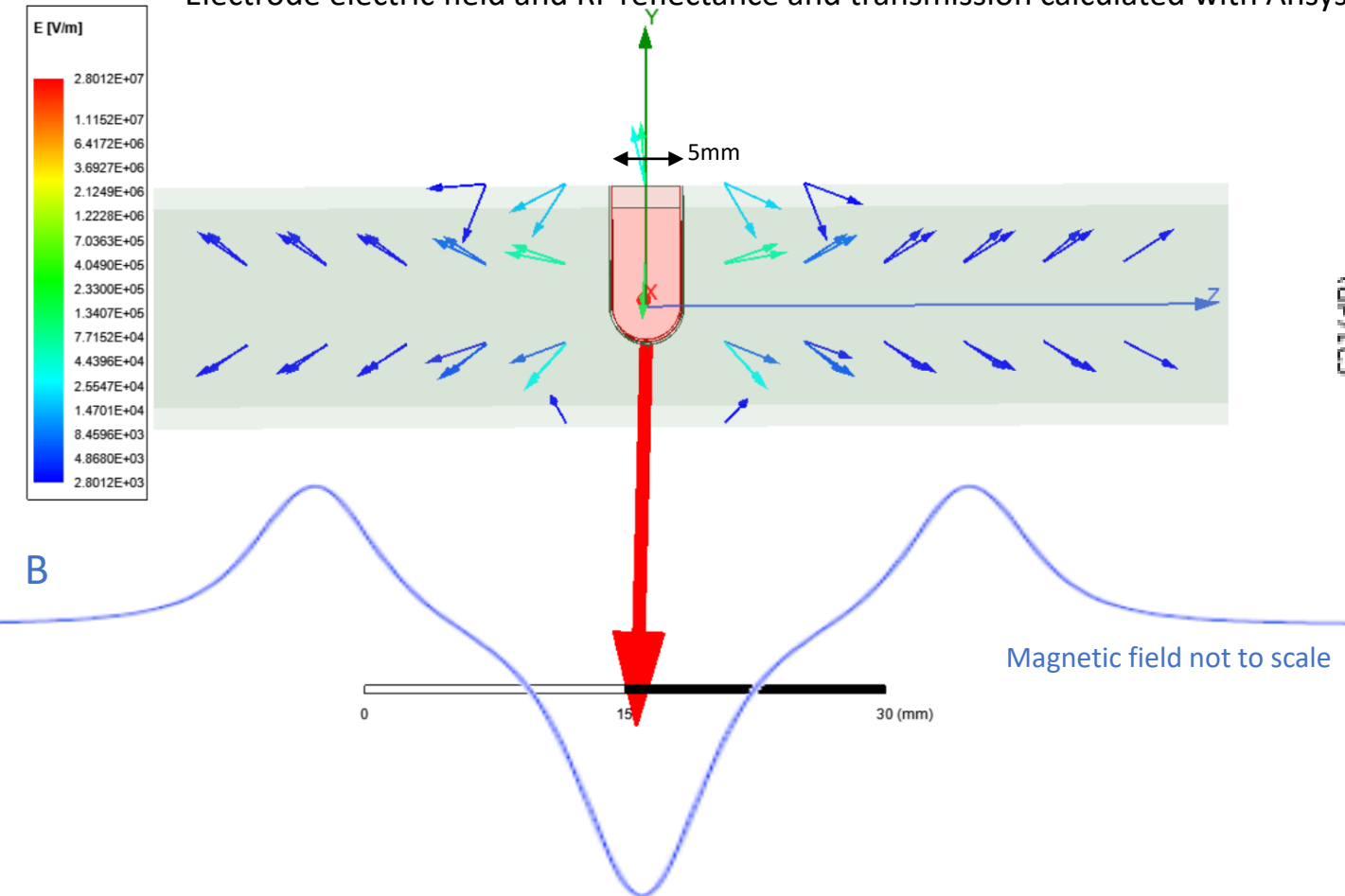
- Emptying less than 0.1ms
- Minimal signal loss $> -1\text{dB}$
 - Signal to Noise ratio decrease of 1
- No disturbance of ambient field
 - > Electrode can be turned on and off, and acts as waveguide when not emptying trap (creates detector noise)
- Compatible with cryogenic and vacuum environment
 - > Electrode is same material as waveguide, and gap is filled with dielectric adhesive with excellent adhesive and low temperature properties (Stycast 2850FT)



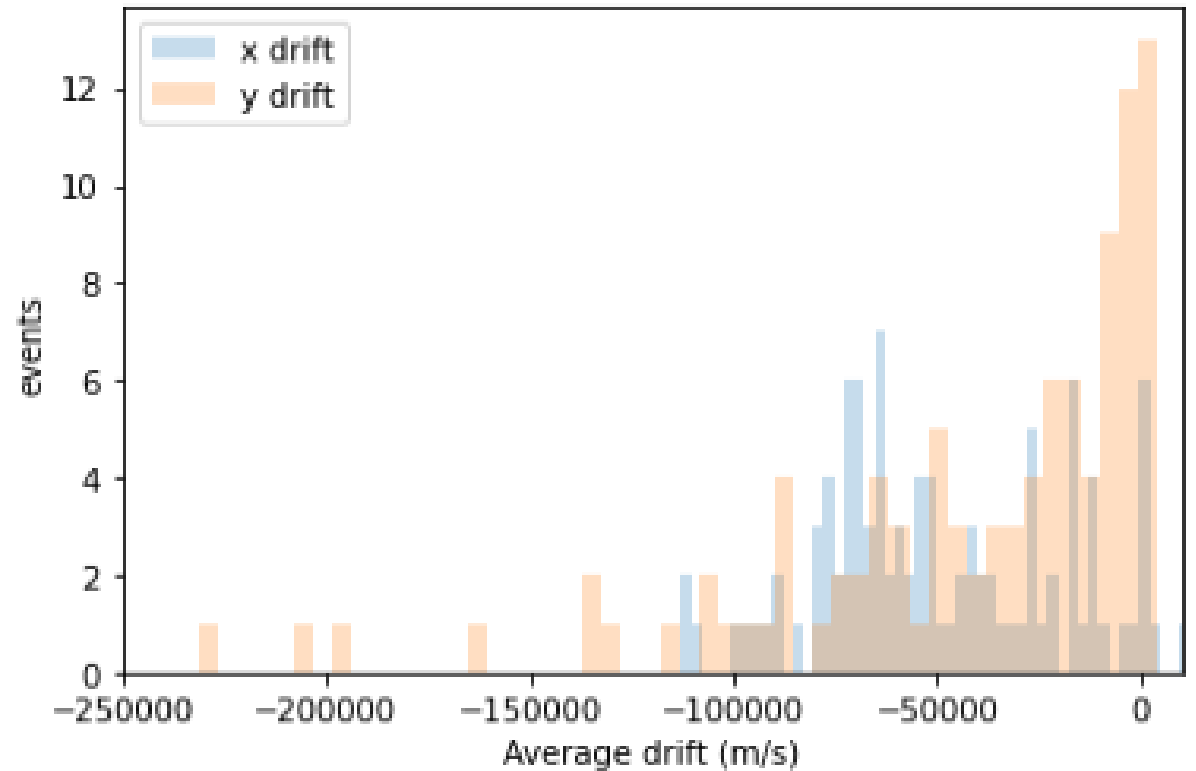
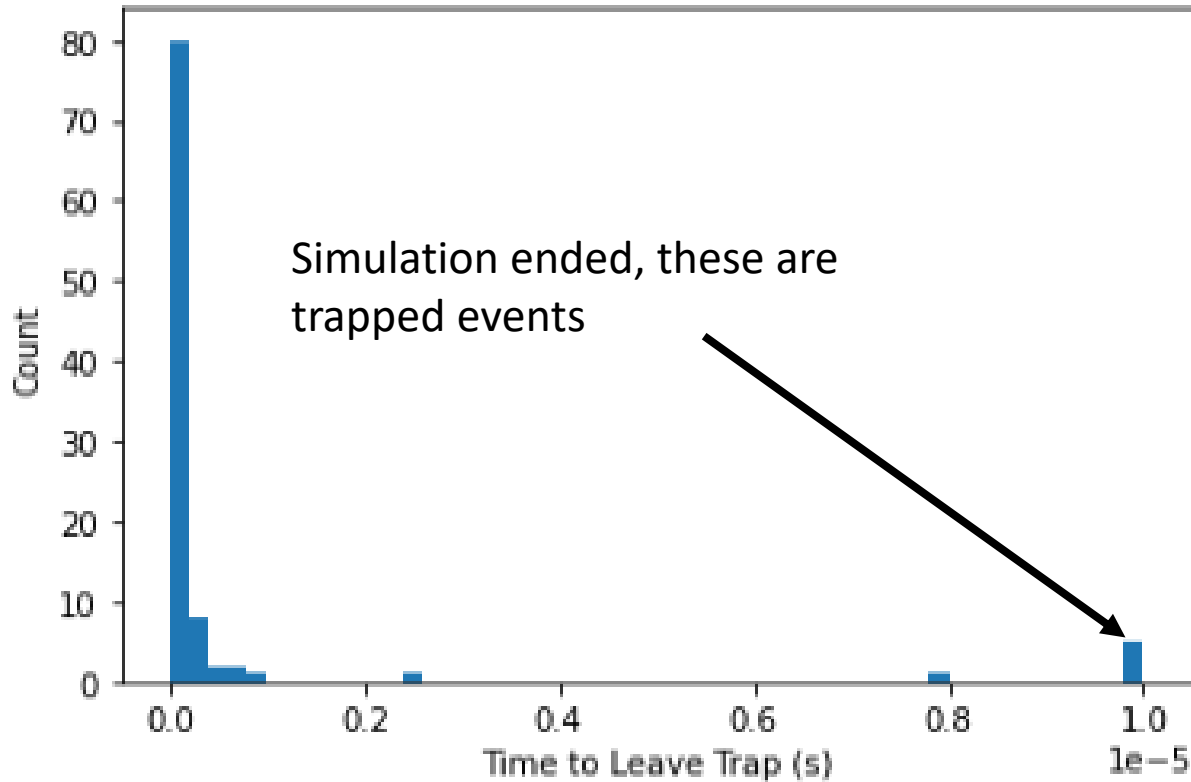
Single electrode ExB sweeper

Non-optimized electrode

Electrode electric field and RF reflectance and transmission calculated with Ansys Maxwell and HFSS respectively.

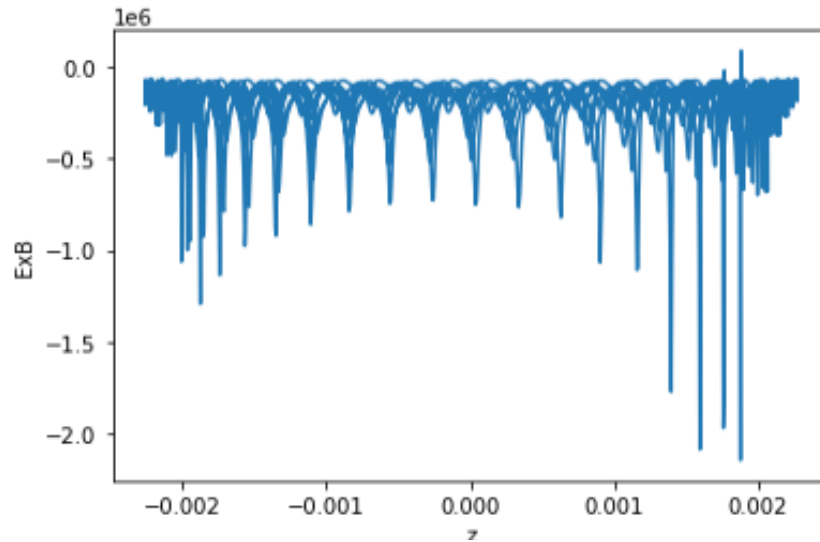


9mm electrode sweep tests

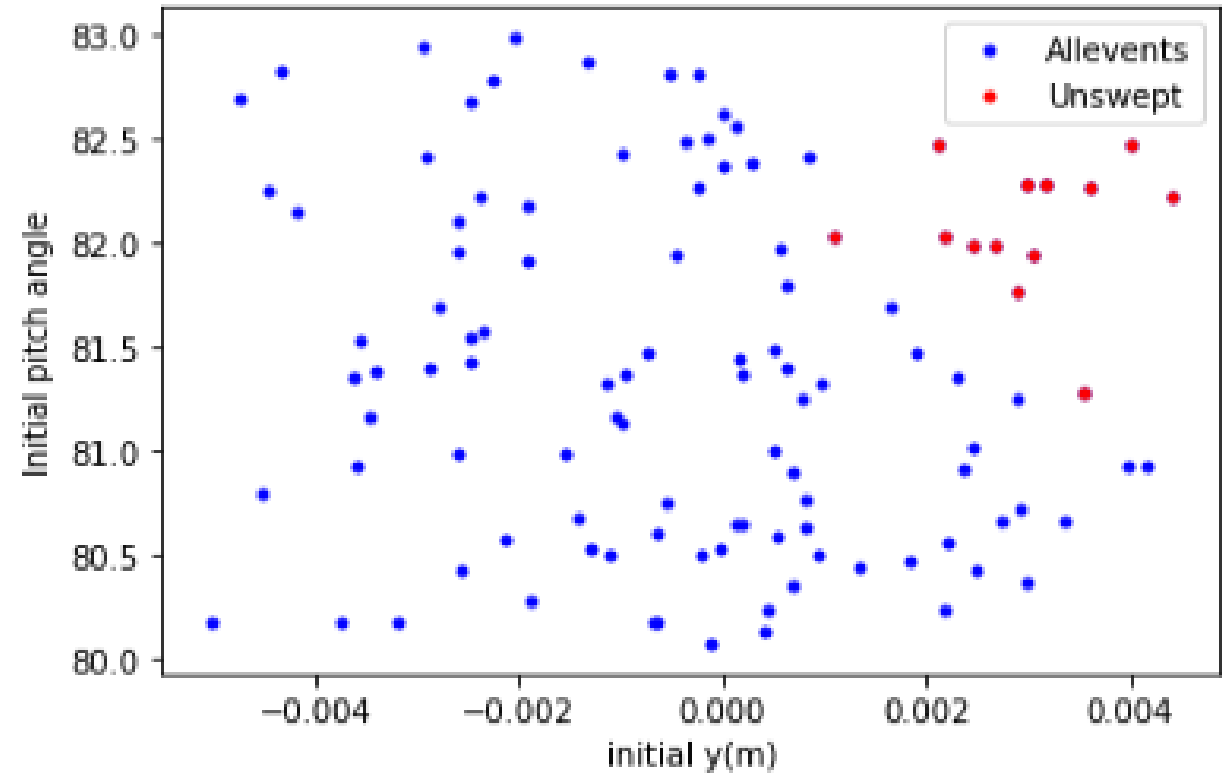
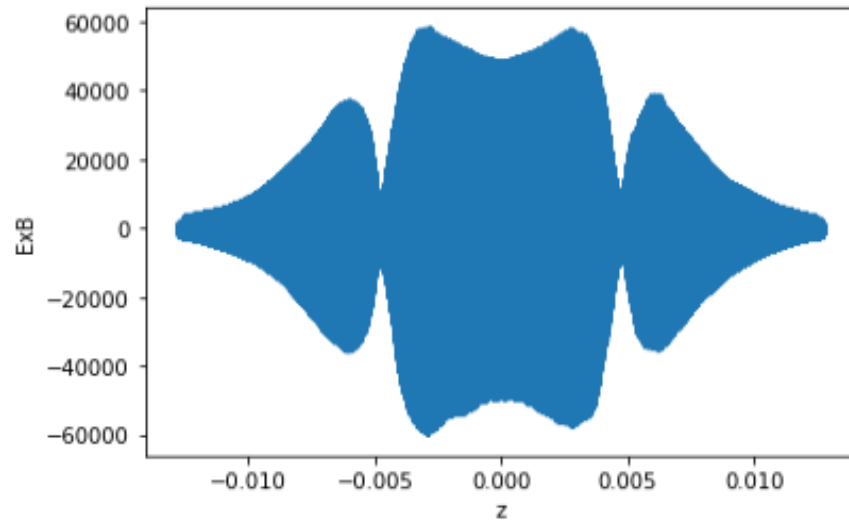


9mm electrode swept vs trapped trajectories

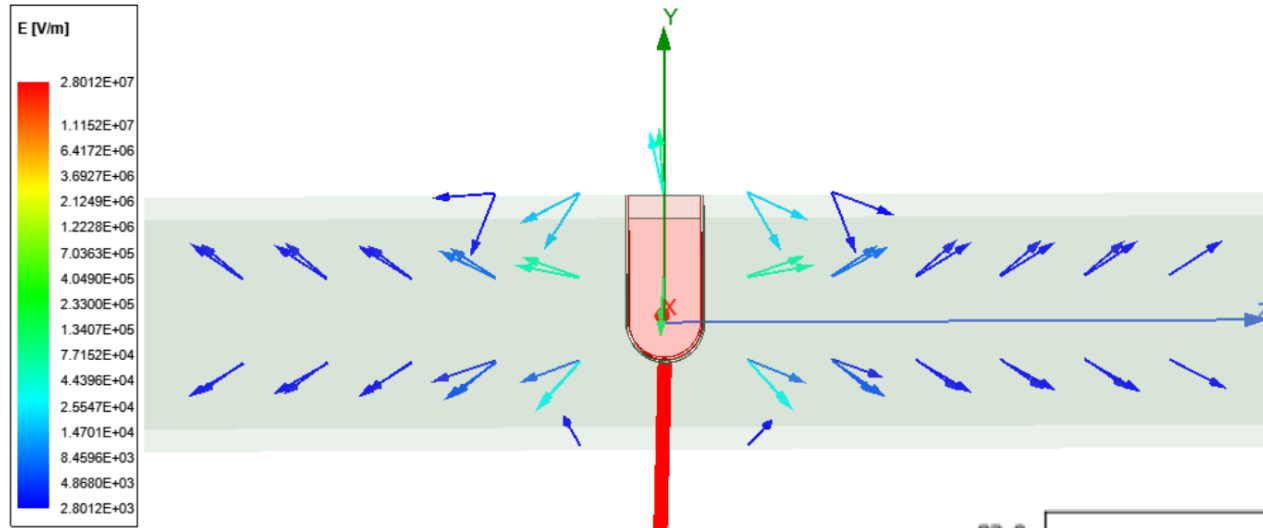
Swept



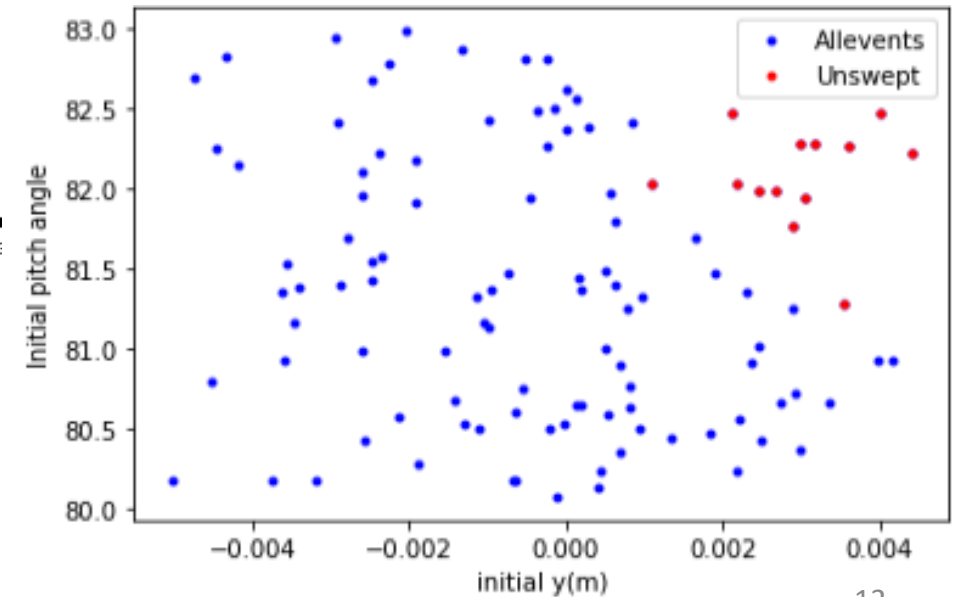
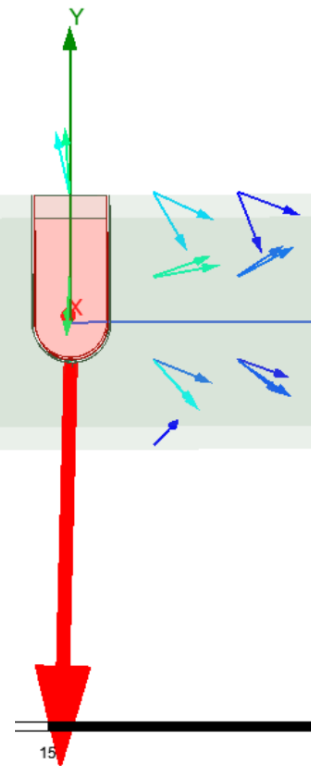
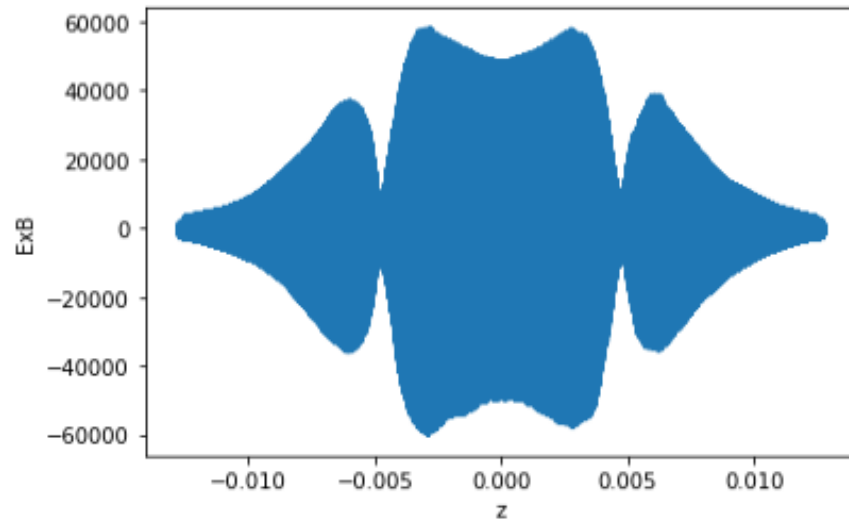
Trapped



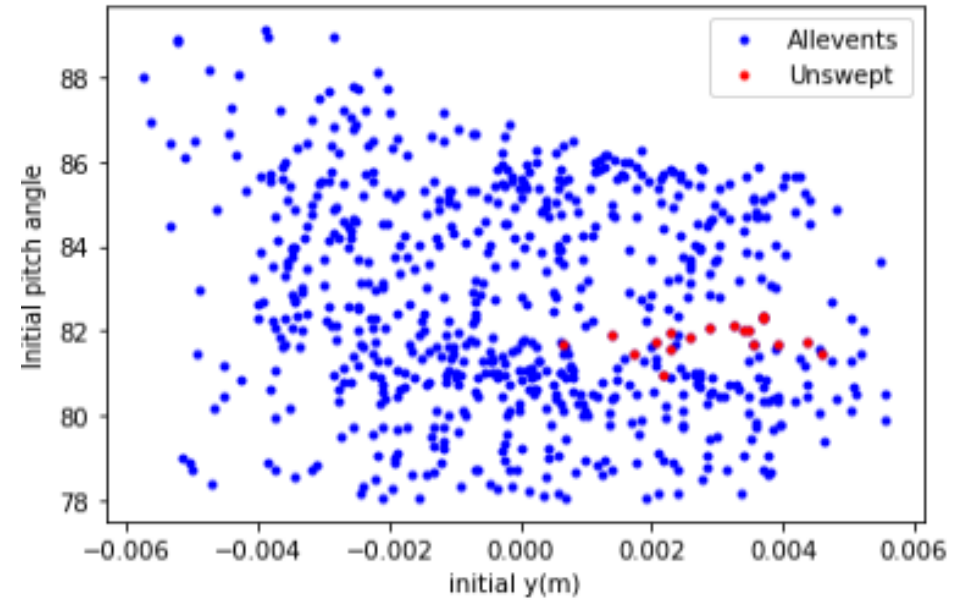
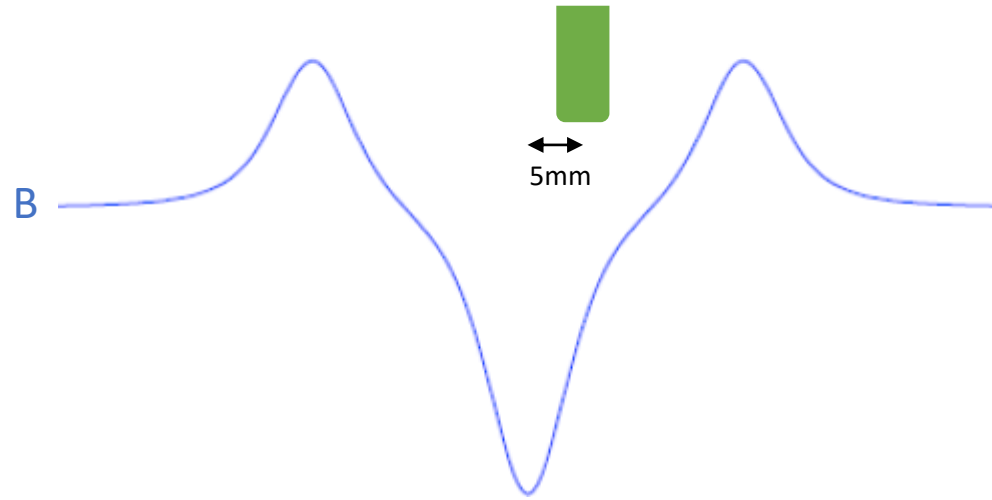
9mm electrode swept vs trapped trajectories



Trapped



Shifted electrode

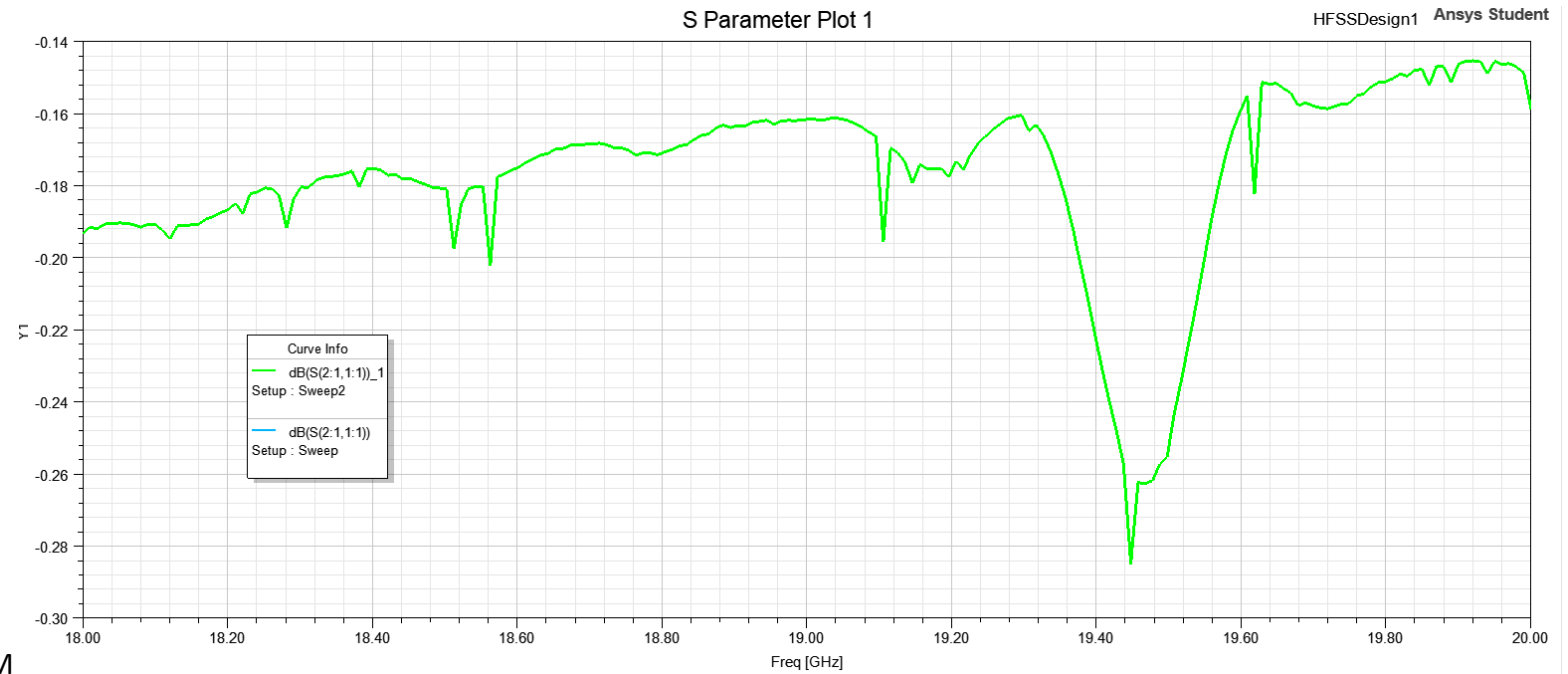
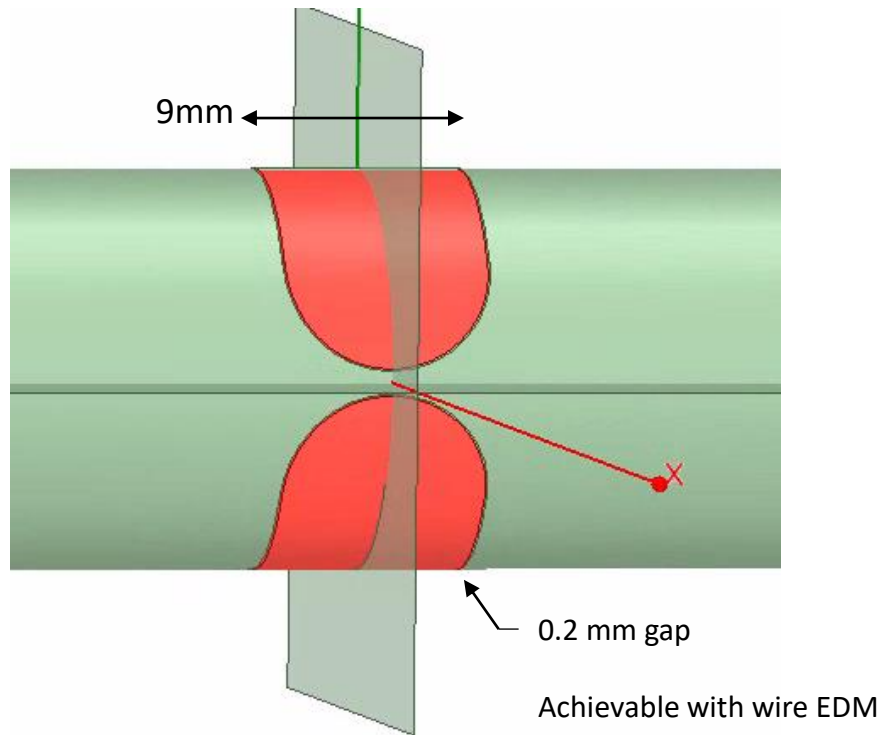


Shifting electrode can improve sweeping from 6% ->1.5%

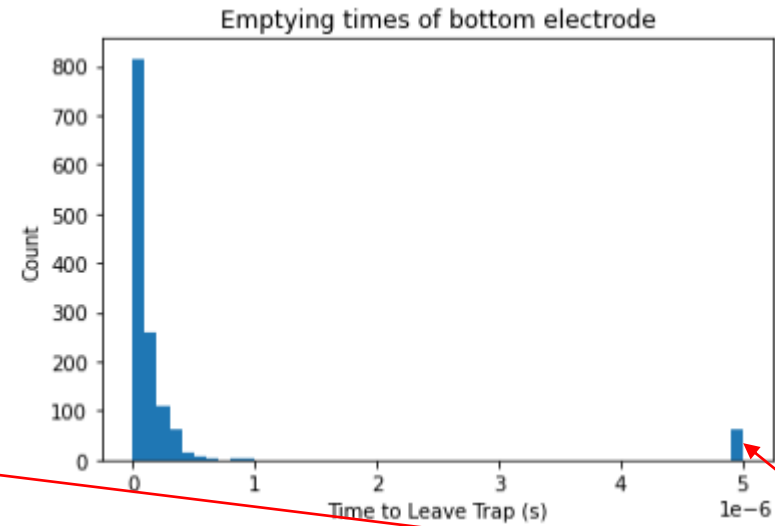
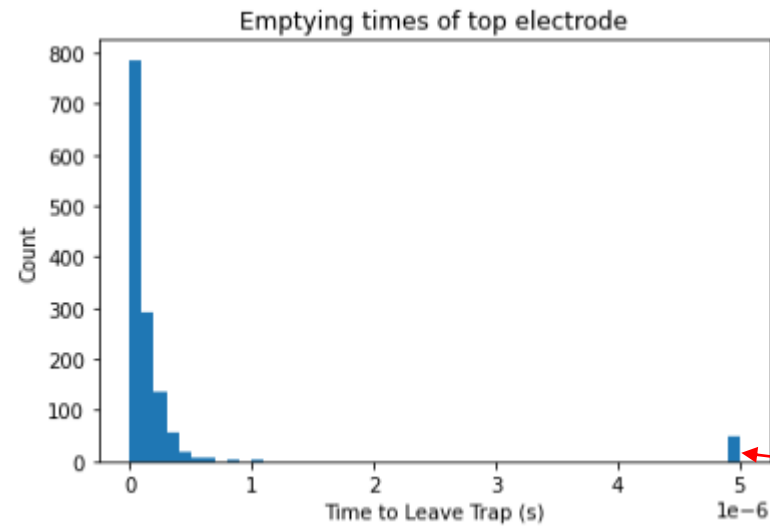
Electrons experience unequal fringe fields

2 electrode design – mirrored electrodes

Inefficient sweeping near electrode, so we can apply voltage to each electrode separately to sweep complete volume



Mirrored electrodes sweeping

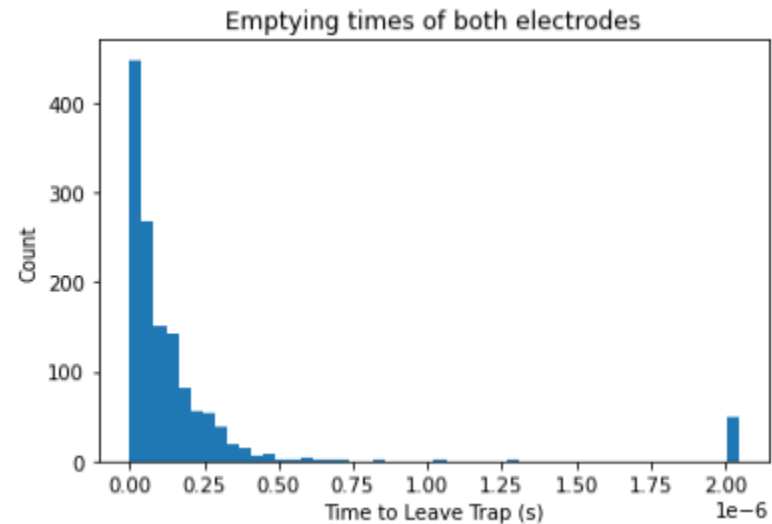


Events not swept by single electrode

Top electrode on from 0-2 μs

Bottom electrode on after 2 μs

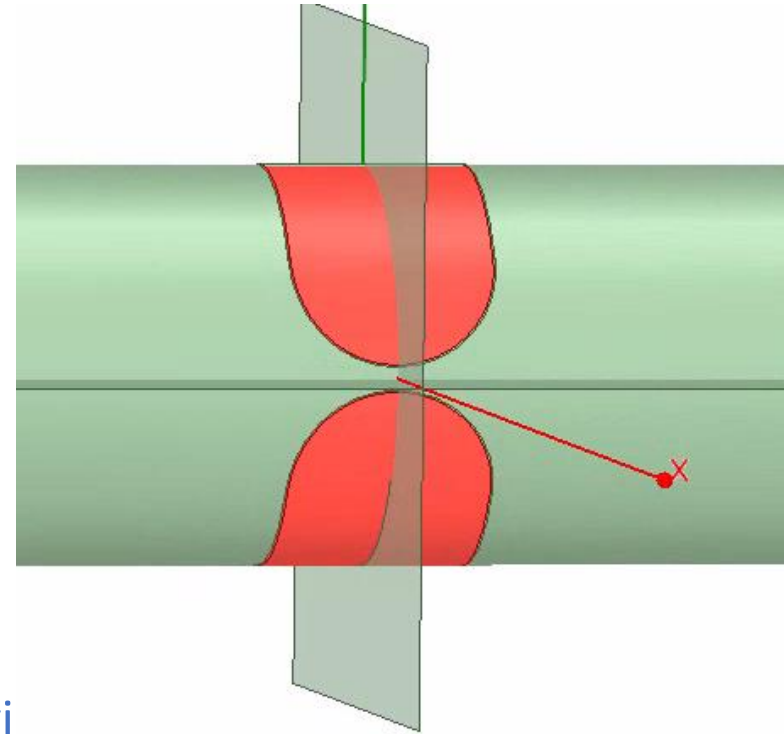
All electrons swept within 2.05 μs



Mirrored electrode design

Trap emptying mechanism requirements

- Emptying less than 0.1ms
 - $O(\mu s)$ trap emptying times
- Minimal signal loss $>-1\text{dB}$
 - -0.3 dB signal loss
- No disturbance of ambient field
 - acts as waveguide when not emptying trap, fast emptying time allows flexibility with voltage timing
- Compatible with cryogenic and vacuum environment
 - Electrodes are same material as the waveguide, gaps are filled with dielectric adhesive with excellent adhesive and low temperature properties (Stycast 2850FT)



^6He -CRES collaboration

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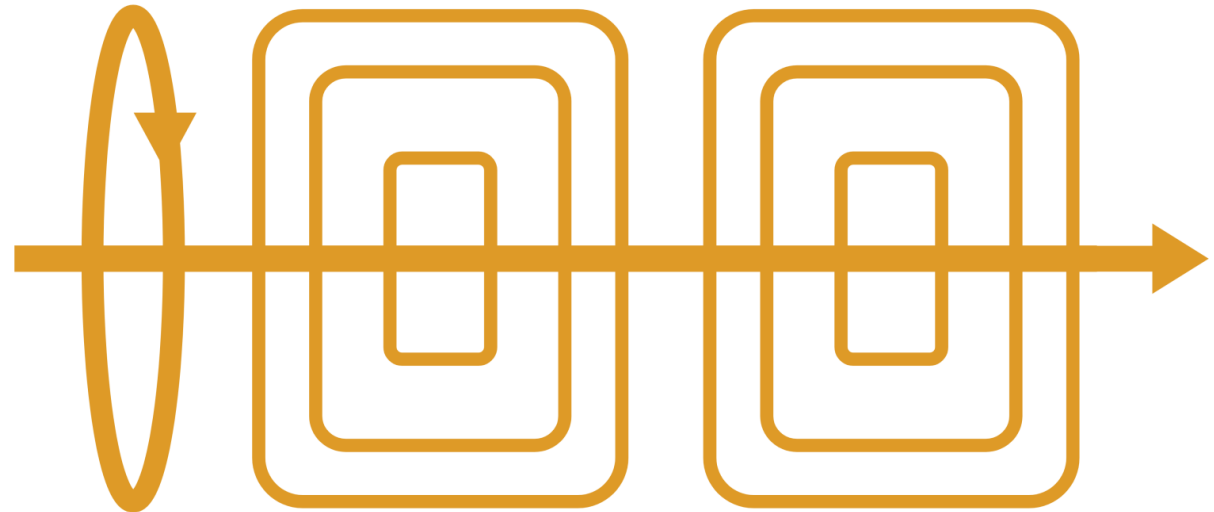
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^6He -CRES



Questions?

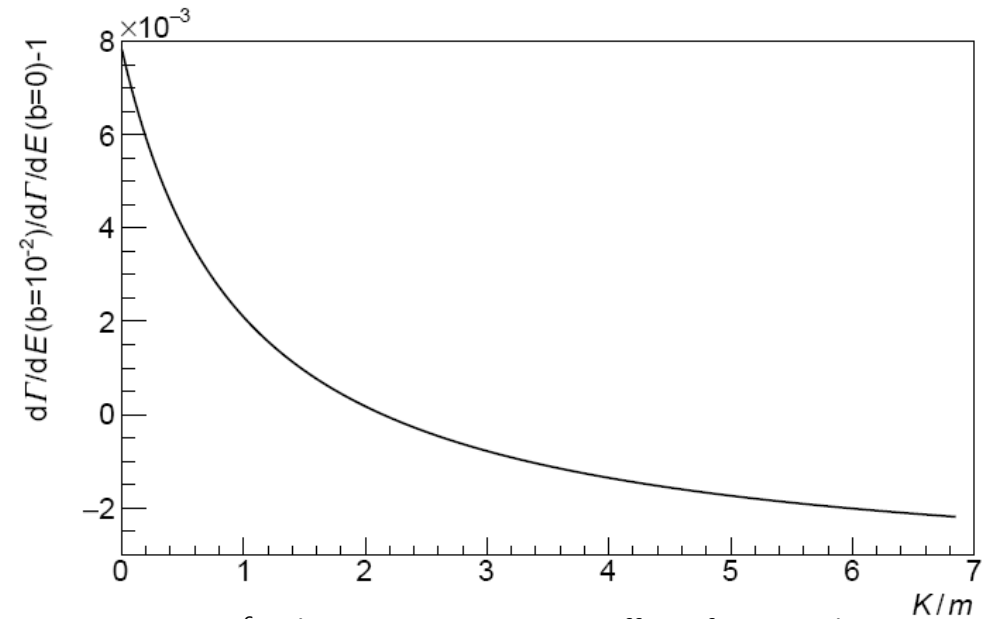
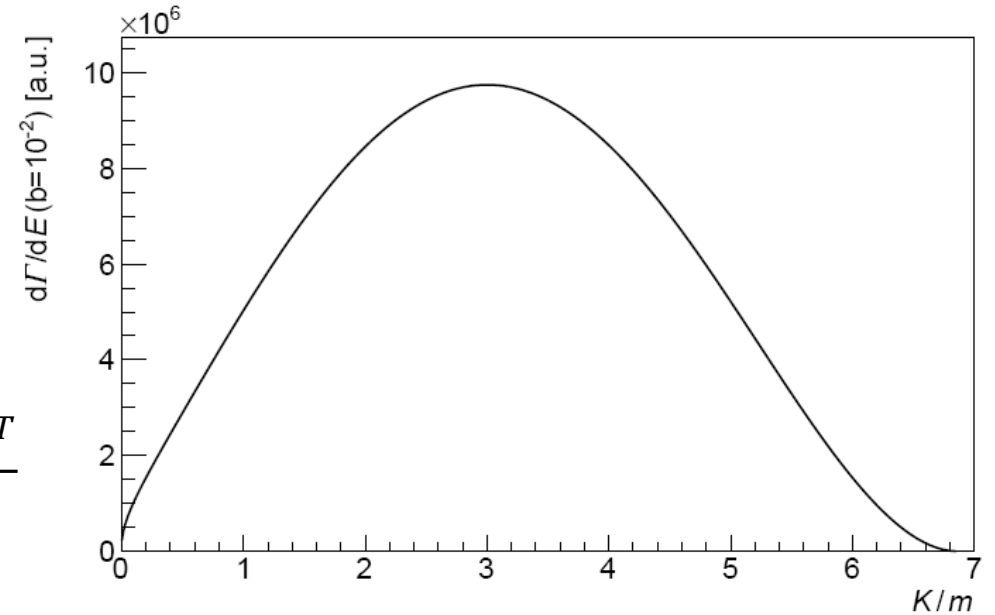
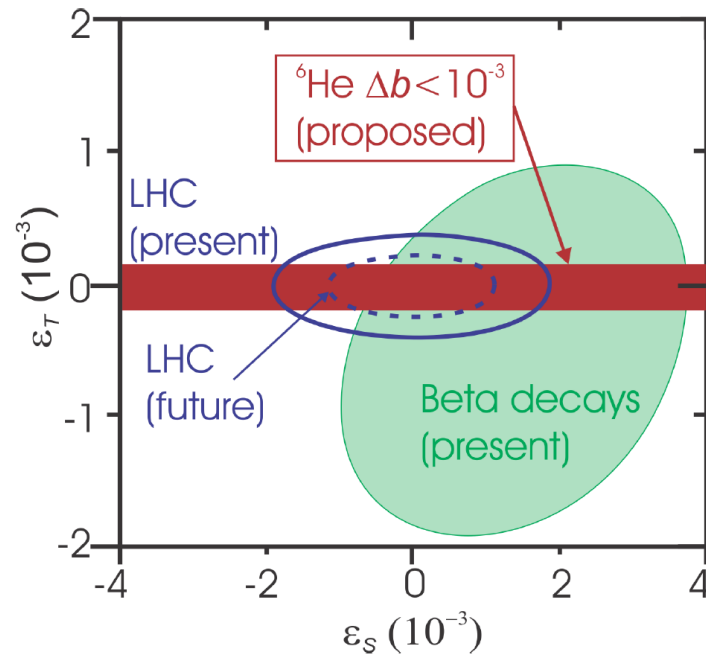
${}^6\text{He}$ CRES experiment

$$\frac{dW}{dE} \approx \frac{dW_0}{dE} \left(1 + \frac{m}{E} b\right)$$

$$g_V = 1 \approx g_T \approx g_S \quad b = \pm 2\sqrt{1 - (\alpha Z)^2} \frac{\epsilon_S - 4 \left(\frac{\langle\sigma\tau\rangle}{\langle\tau\rangle}\right)^2 g_A \epsilon_T}{1 + \left(\frac{\langle\sigma\tau\rangle}{\langle\tau\rangle}\right)^2 g_A^2}$$

$$C_i = \left(\frac{G_F V_{ud}}{\sqrt{2}}\right) \bar{C}_i$$

$$\bar{C}_T = 8g_T \epsilon_T$$



Top: ${}^6\text{He}$ beta spectrum Bottom: effect of nonzero b